

## **Description**

These N-Channel enhancement mode power field effect transistors are using split gate trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and with stand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

#### **Features**

- 100V,12.6A,  $R_{DS(on),max} = 9.8 \text{m}\Omega @V_{GS} = 10V$
- Improved dv/dt capability
- Fast switching
- ♦ 100% EAS Guaranteed
- Green device available

## **Applications**

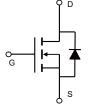
- Motor Drives
- UPS
- ♦ DC-DC Converter

# **Product Summary**

 $\begin{array}{ll} V_{DSS} & 100V \\ R_{DS(on),max} @ V_{GS} {=} 10V & 9.8 m\Omega \\ I_D & 12.6 A \end{array}$ 

## **Pin Configuration**





SOP-8

Schematic

## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V <sub>DSS</sub>	100	V
Continuous drain current ( T <sub>A</sub> = 25°C )		12.6	Α
( T <sub>A</sub> = 100°C )	I <sub>D</sub>	8	Α
Pulsed drain current <sup>1)</sup>	I <sub>DM</sub>	37.8	Α
Gate-Source voltage	V <sub>GSS</sub>	±20	V
Avalanche energy <sup>2)</sup>	Eas	3.2	mJ
Power Dissipation	P <sub>D</sub>	3.1	W
Storage Temperature Range	T <sub>STG</sub>	-55 to +150	°C
Operating Junction Temperature Range	TJ	-55 to +150	°C

### **Thermal Characteristics**

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R <sub>eJC</sub>	24	°C/W
Thermal Resistance Junction-to-Ambient	Reja	40	°C/W



# **Package Marking and Ordering Information**

Device	Device Package	Marking
VST10N098-S8	SOP-8	VST10N098-S8

# Electrical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0 V, I <sub>D</sub> =250uA	100			V
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	1.2	1.7	2.5	V
Drain-source leakage current	I <sub>DSS</sub>	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0V			1	μΑ
Gate leakage current, Forward	I <sub>GSSF</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V			100	nA
Gate leakage current, Reverse	I <sub>GSSR</sub>	V <sub>GS</sub> =-20 V, V <sub>DS</sub> =0 V			-100	nA
Drain-source on-state resistance		V <sub>GS</sub> =10 V, I <sub>D</sub> =11.5 A		7.4	9.8	mΩ
	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5 V, I <sub>D</sub> =9.5 A		9.6	13	mΩ
Forward transconductance	g <sub>fs</sub>	V <sub>DS</sub> =5V , I <sub>D</sub> =11.5A		46.5		S
Dynamic characteristics						
Input capacitance	C <sub>iss</sub>	V 50VV 0V		2553		pF
Output capacitance	Coss	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$ $V_{DS} = 10 \text{ MHz}$		308		
Reverse transfer capacitance	Crss	F - IIVIDZ		13.5		
Turn-on delay time	t <sub>d(on)</sub>			9.3		ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> = 50V,V <sub>GS</sub> =10V, I <sub>D</sub> = 11.5A		4.2		
Turn-off delay time	t <sub>d(off)</sub>	R <sub>G</sub> =3Ω		35.8		
Fall time	t <sub>f</sub>			6.2		
Gate charge characteristics						
Gate to source charge	Q <sub>gs</sub>	V 50V L 44.5A		8.5		
Gate to drain charge	Q <sub>gd</sub>	$V_{DS}$ =50V, $I_{D}$ =11.5A, $V_{GS}$ = 10 V		3.8		nC
Gate charge total	Qg			38		
Drain-Source diode characteris	tics and Maxi	mum Ratings				
Continuous Source Current	Is				2.5	А
Pulsed Source Current <sup>3)</sup>	Ism				7.5	Α
Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =11.5A, T <sub>J</sub> =25°C			1.2	V
Reverse recovery time	t <sub>rr</sub>	I <sub>F</sub> =11.5A,dI <sub>F</sub> /dt=100 A/μs		28.5		ns
Reverse recovery charge	Qrr			123		nC

#### Notes:

- 1: Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2:  $V_{DD} {=} 25 V,\, V_{GS} {=} 10 V,\, L {=} 0.1 mH,\, I_{AS} {=} 8 A,\, Starting\, T_J {=} 25\,^{\circ}\!\! C\,.$
- 3: Pulse Test: Pulse Width  $\leq$ 300  $\upmu$  s, Duty Cycle  $\leq$ 2%.



## **Electrical Characteristics Diagrams**

Figure 1. Typ. Output Characteristics

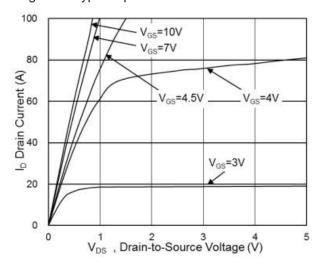


Figure 3. Capacitance Characteristics

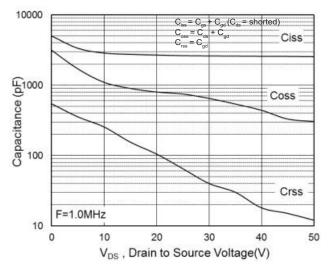


Figure 5. Body-Diode Characteristics

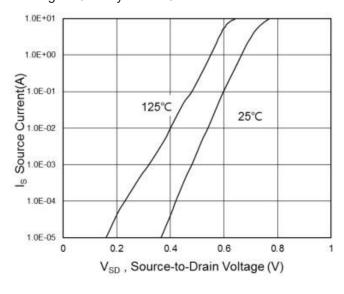


Figure 2. Transfer Characteristics

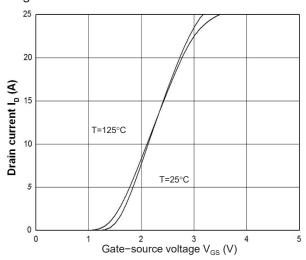


Figure 4. Gate Charge Waveform

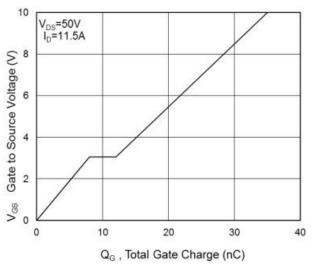


Figure 6. Rdson-Drain Current

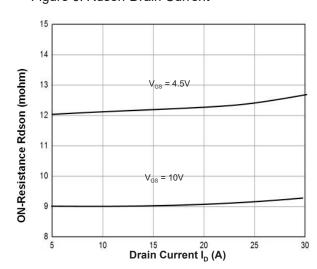




Figure 7. Rdson-Junction Temperature

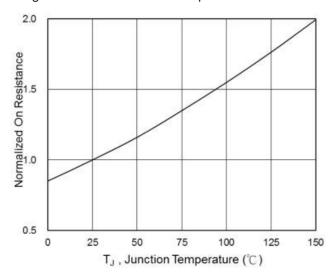


Figure 8. V<sub>GS(th)</sub>-Junction Temperature

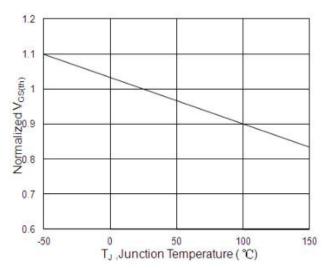


Figure 9. On-Resistance vs. Gate-to-Source voltage

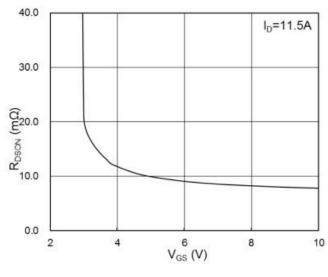


Figure 10: Safe Operating Area

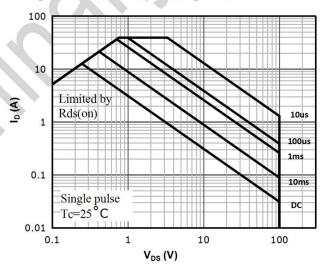
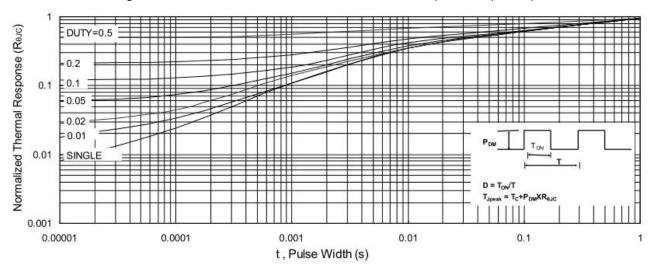


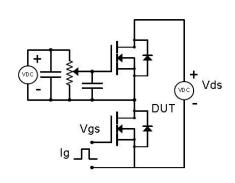
Figure 11. Normalized Maximum Transient Thermal Impedance (RthJC)

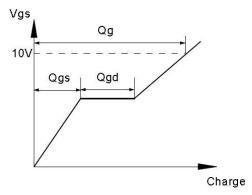




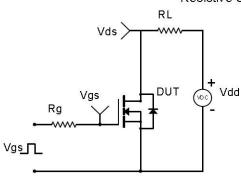
# **Test Circuit & Waveform**

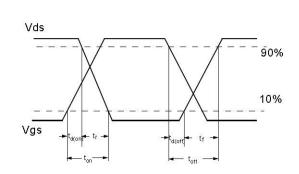
# Gate Charge Test Circuit & Waveform



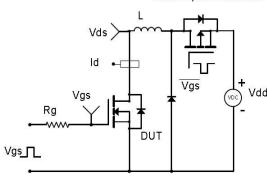


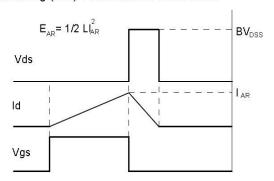
Resistive Switching Test Circuit & Waveforms





Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms

